

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) TWI-11120	Application Number NEW	
				Applicant(s) John J. Sidorowich		
				Filing Date HEREWITH	Group Art Unit Unknown	

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
SN	*AA	4,999,509	03/12/1991	Wada et al.	250	559.27	03/26/1990
N	*AB	5,148,513	09/15/1992	Koza et al.	706	13	09/18/1990
	*AC	5,222,192	06/22/1993	Shaefer	706	13	09/03/1992
	*AD	5,249,259	09/28/1993	Harvey	706	13	05/28/1992
	*AE	5,255,345	10/19/1993	Shaefer	706	13	09/01/1992
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	*AG	5,394,509	02/28/1995	Winston	706	13	03/31/1992
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	*AI	5,493,401	02/20/1996	Horie et al.	356	632	09/20/1994
	*AJ	5,541,848	07/30/1996	McCormack	700	213	12/15/1994
	*AK	5,568,590	10/22/1996	Tolson	706	13	12/17/1993
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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

SN	*AT	R.A. Sequeira et al., "Automating the parameterization of mathematical models using genetic algorithms," <i>Computer and Electronics in Agriculture</i> , 1994, Vol. 11, pp. 265-290.
↑	*AU	E. Michielssen et al., "Optimal multilayer filter design using real coded genetic algorithms," <i>IEE Proceedings-J</i> , Dec. 1992, Vol. 139, No. 6, pp. 413-420.
	*AV	T. Eisenhamer et al., "Optimization of interference filters with genetic algorithms applied to silver-based heat mirrors," <i>Applied Optics</i> , Nov. 1, 1993, Vol. 32, No. 31, pp. 6310-6315.
	*AW	S. Martin et al., "Simulated Darwinian evolution of homogeneous multilayer systems: a new method for optical coatings design," <i>Optics Communications</i> , Sep. 1, 1994, Vol. 110, No. 5/6, pp. 503-506.
	*AX	K. Rabinovitch et al., "Genetic algorithm and thin-film design," <i>Proceedings SPIE</i> , July 1994, Vol. 2262, pp. 163-174.
	*AY	S. Martin et al., "Synthesis of optical multilayer systems using genetic algorithms," <i>Applied Optics</i> , May 1, 1995, Vol. 34, No. 13, pp. 2247-2254.
	*AZ	T. Bäck et al., "Evolution Strategies for Mixed-Integer Optimization of Optical Multilayer Systems," <i>Proceedings Fourth Annual Conference on Evolutionary Programming</i> , 1995, pp. 33-51.
↓	*BA	D.J. Mikulin et al., "Fitting reflectivity data from liquid crystal cells using genetic algorithms," <i>Liquid Crystals</i> , 1997, Vol. 22, No. 3, pp. 301-307.
SN	*BB	M. Mitchell, "Genetic Algorithms: An Overview," <i>Complexity</i> , 1995, Vol. 1, No. 1, pp. 31-39.

Examiner	<i>Sandy J. M.</i>	Date Considered	<i>11/08/05</i>
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>		Docket Number (Optional) TWI-11110	Application Number NEW
		Applicant(s) John J. Sidorowich	
		Filing Date HEREWITH	Group Art Unit Unknown

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
SN	*BC	6,532,076	03/11/2003	Sidorowich	356	630	04/04/2000

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	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	No

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SN	*BD	J.R. Koza, "Introduction to Genetic Algorithms," from <i>Genetic Programming</i> , Chapter 3, pp. 17-22 and 29.
	*BE	J.H. Holland, "Genetic Algorithms," <i>Scientific American</i> , July 1992, pp. 66-72.
	*BF	R.L. Riolo, "Survival of the Fittest Bits," <i>Scientific American</i> , July 1992, pp. 114-116.
	*BG	J.T. Fanton et al., "Multiparameter measurements of thin films using beam-profile reflectometry," <i>J. Appl. Phys.</i> , 1 June 1993, Vol. 73, No. 11, pp. 7035-7040.
	*BH	J.M. Leng et al., "Simultaneous measurement of six layers in a silicon on insulator film stack using spectrophotometry and beam profile reflectometry," <i>J. Appl. Phys.</i> , 15 April 1997, Vol. 81, No. 8, pp. 3570-3578.
	*BI	E.A. Rietman et al., "A Genetic Algorithm for Low Variance Control in Semiconductor Device Manufacturing: Some Early Results," <i>IEEE Transactions on Semiconductor Manufacturing</i> , May 1996, Vol. 9, No. 2, pp. 223-229.
SN	*BJ	J.F. Tang et al., "Automatic design and optical thin-film systems—merit function and numerical optimization method," <i>J. Opt. Soc. Am.</i> , Nov. 1982, Vol. 72, No. 11, pp. 1522-1528.

Examiner	<i>Snyder</i>	Date Considered	<i>11/18/05</i>
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